

Notice of References Cited	Application/Control No. 10/684,777	Applicant(s)/Patent Under Reexamination DEECHER ET AL.	
	Examiner Jennifer Kim	Art Unit 1617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0036923 a1	02-2003	Waldon et al.	705/2
*	B	US-2003/0216366 a1	11-2003	Leonard et al.	514/182
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

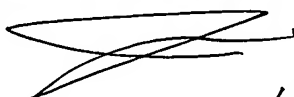
FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO98/36744	08-1998	PCT	BRILEY	-----
	O					
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	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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